

WHAT IS CLAIMED IS:

1. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency of an input-impedance-versus-frequency characteristic of the piezoelectric transformer; and

selecting the characteristic of the piezoelectric transformer based on the value of the measured resonant frequency.

2. The method according to claim 1, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

3. The method according to claim 1, wherein only the

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input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

4. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a bandwidth of an input-impedance-versus-frequency characteristic of the piezoelectric transformer by subtracting a resonant-frequency f_r from an antiresonant-frequency f_a ; and

selecting the characteristic of the piezoelectric transformer based on the value of the measured bandwidth.

5. The method according to claim 4, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

6. The method according to claim 4, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

7. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant resistance from an input-impedance-versus-frequency characteristic of the piezoelectric transformer; and

selecting the characteristic of the piezoelectric transformer based on the value of the measured resonant resistance.

8. The method according to claim 7, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

9. The method according to claim 7, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

10. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency, a bandwidth, and a resonant resistance from an input-impedance-versus-frequency characteristic of the piezoelectric transformer in which the bandwidth is determined by subtracting a resonant-frequency f_r from an antiresonant-frequency f_a ; and

selecting the characteristic of the piezoelectric transformer based on the values of the measured resonant frequency, the bandwidth, and the resonant resistance.

11. The method according to claim 10, wherein the step of measuring the piezoelectric transformer is done while the

piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

12. The method according to claim 10, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

13. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency of an input-impedance-versus-frequency characteristic of the piezoelectric transformer; and

selecting the characteristic of the piezoelectric transformer based on the value of the measured resonant frequency.

14. The method according to claim 13, wherein the step

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of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

15. The method according to claim 13, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

16. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a bandwidth of an input-impedance-versus-frequency characteristic of the piezoelectric transformer by subtracting a resonant-frequency from an antiresonant-frequency; and

selecting the characteristic of the piezoelectric transformer based on the value of the measured bandwidth.

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17. The method according to claim 16, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

18. The method according to claim 16, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

19. A method for selecting a piezoelectric transformer characteristic, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant resistance of an input-impedance-versus-frequency-characteristic of the piezoelectric transformer; and

selecting the characteristic of the piezoelectric transformer based on the value of the measured resonant resistance.

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21. The method according to claim 19, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

measuring a resonant frequency, a bandwidth, and a resonant resistance of an input-impedance-versus-frequency characteristic of the piezoelectric transformer in which the bandwidth is determined by subtracting a resonant-frequency from an antiresonant-frequency; and

selecting the characteristic of the piezoelectric

23. The method according to claim 22, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

24. The method according to claim 22, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.